

UNISONIC TECHNOLOGIES CO., LTD

1N70Q-TA Power MOSFET

1.0A, 700V N-CHANNEL POWER MOSFET

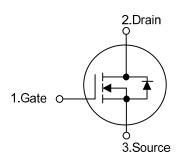
DESCRIPTION

The UTC **1N70Q-TA** is a high voltage MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient AC to DC converters and bridge circuits.

■ FEATURES

- * $R_{DS(ON)} \le 12 \Omega$ @ $V_{GS} = 10V$, $I_D = 0.5A$
- * Fast switching capability
- * Avalanche energy specified
- * Improved dv/dt capability, high ruggedness

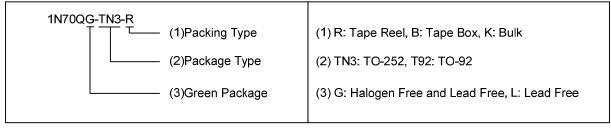
■ SYMBOL

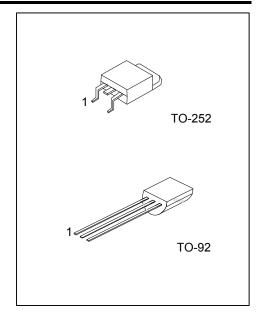


ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
1N70QL-TN3-R	1N70QG-TN3-R	TO-252	G	D	S	Tape Reel	
1N70QL-T92-B	1N70QG-T92-B	TO-92	G	D	S	Tape Box	
1N70QL-T92-K	1N70QG-T92-K	TO-92	G	D	S	Bulk	

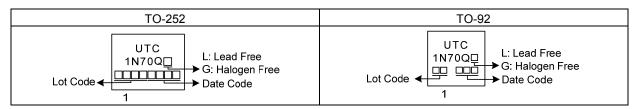
Note: Pin Assignment: G: Gate D: Drain S: Source





1N70Q-TA

■ MARKING



1N70Q-TA

■ ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V _{DSS}	700	V	
Gate-Source Voltage		V_{GSS}	± 30	V	
Drain Current	Continuous	I_D	1	А	
	Pulsed (Note 2)	I _{DM} 2		Α	
Avalanche Current (Note 2)		I _{AR}	1.3	Α	
Avalanche Energy (Note 3)	anche Energy (Note 3) Single Pulsed		27	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.2	V/ns	
Power Dissipation	TO-252		39.5	W	
	TO-92	P _D	2.2	W	
Junction Temperature		TJ	+150	°C	
Storage Temperature		T _{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 30mH, I_{AS} = 1.3A, V_{DD} = 60V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C
- 4. $I_{SD} \le 1.0$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25$ °C

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT	
Junction to Ambient	TO-252	0	110	°C/W	
	TO-92	θ_{JA}	160	°C/W	
Junction to Case	TO-252	0	3.16	°C/W	
	TO-92	θ_{JC}	56.8	°C/W	

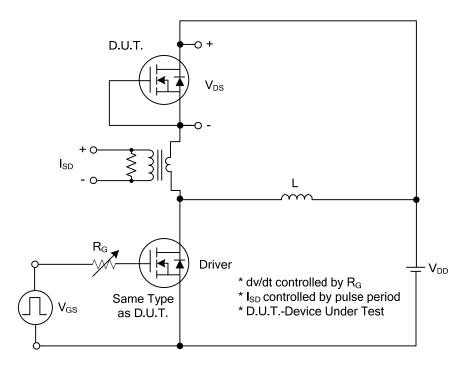
■ **ELECTRICAL CHARACTERISTICS** (T_J=25°C, unless otherwise specified.)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS			•				
Drain-Source Breakdown Voltage		BV _{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	700			V
Drain-Source Leakage Current		I_{DSS}	$V_{DS} = 700V, V_{GS} = 0V$			10	μΑ
Gate-Source Leakage Current	Forward	- I _{GSS}	$V_{GS} = 30V, V_{DS} = 0V$			100	nΑ
	Reverse		$V_{GS} = -30V, V_{DS} = 0V$			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}$, $I_D = 250\mu A$	2.0		4.0	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	$V_{GS} = 10V, I_D = 0.5A$			12	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance	put Capacitance				140.1		pF
Output Capacitance		Coss	V_{GS} =0V, V_{DS} =25V, f=1MHz		20.3		pF
Reverse Transfer Capacitance		C_{RSS}			2.3		pF
SWITCHING CHARACTERISTIC	S						
Total Gate Charge (Note 1)		Q_G	V _{DS} =560V, V _{GS} =10V, I _D =1A,		8.9		nC
Gate to Source Charge		Q_{GS}	$I_{G}=1$ mA (Note 1, 2)		3.7		nC
Gate to Drain Charge		Q_{GD}	IG-IIIA (Note 1, 2)		1.1		nC
Turn-ON Delay Time (Note 1)		t _{D(ON)}			4.1		ns
Rise Time		t _R	V_{DD} =100V, V_{GS} =10V, I_{D} =1A,		16.3		ns
Turn-OFF Delay Time		$t_{D(OFF)}$	R_G =25 Ω (Note 1, 2)		16.4		ns
Fall-Time		t_{F}			38.3		ns
SOURCE- DRAIN DIODE RATIN	GS AND CH	ARACTERIST	ŢICS				
Maximum Body-Diode Continuous Current		Is				1	Α
Maximum Body-Diode Pulsed Current		I_{SM}				2	Α
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	V _{GS} =0V, I _S =1.0A			1.4	V
Body Diode Reverse Recovery Time (Note 1)		t _{rr}	V _{GS} =0V, I _S =1.0A,		166		nS
Body Diode Reverse Recovery Charge		Q_{rr}	dI _F / dt =100A/μs		952.3		nC

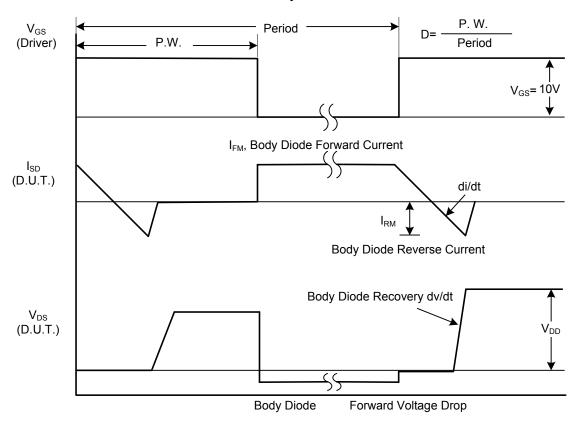
Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%.

^{2.} Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS



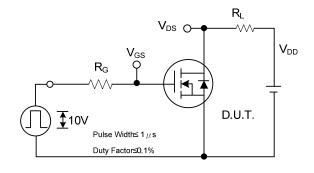
Peak Diode Recovery dv/dt Test Circuit

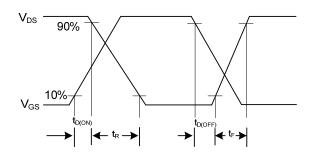


Peak Diode Recovery dv/dt Waveforms

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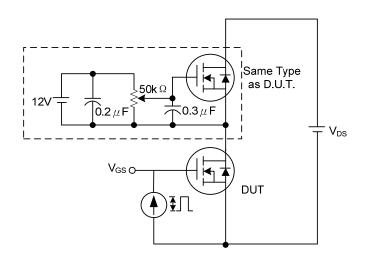
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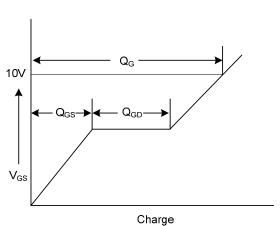




Switching Test Circuit

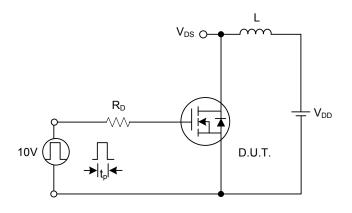
Switching Waveforms

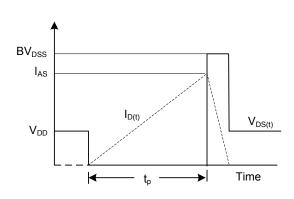




Gate Charge Test Circuit

Gate Charge Waveform

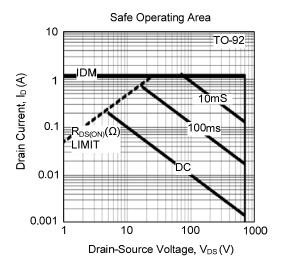




Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

■ TYPICAL CHARACTERISTICS



UTC assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all UTC products described or contained herein. UTC products are not designed for use in life support appliances, devices or systems where malfunction of these products can be reasonably expected to result in personal injury. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner. UTC reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.